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05/08/97  
Class Subclass  
ISSUE CLASSIFICATION  
SCANNED 5

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UTILITY SERIAL NUMBER  
PATENT DATE  
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6231427

SERIAL NUMBER 08/853,323 FILING DATE 05/08/97 CLASS 451 SUBCLASS 451 GROUP ART UNIT 24203 EXAMINER Nguyen

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\*\*CONTINUING DATA\*\*  
VERIFIED THIS APPLN IS A DIV OF 08/759,172 12/03/96 PAT 5,692,947  
WHICH IS A CON-OF 08/287,658 08/09/94 ABANDONED.  
GN

\*\*FOREIGN/PCT APPLICATIONS\*\*  
VERIFIED  
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FOREIGN FILING LICENSE GRANTED 10/01/97

Foreign priority claimed 35 USC 119 conditions met ☐ yes ☒ no  
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TITLE LINEAR POLISHER AND METHOD FOR SEMICONDUCTOR WAFER PLANARIZATION

U.S. DEPT. OF COMM./ PAT. & TM—PTO-436L (Rev.12-84)

PARTS OF APPLICATION FILED SEPARATELY  
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STAPLE

AREA

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PATENT NUMBER

ORIGINAL CLASSIFICATION

CLASS SUBCLASS

451 041

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APPLICANT'S NAME (PLEASE PRINT)

Talieh, et al

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CROSS REFERENCE(S)

CLASS

SUBCLASS

(ONE SUBCLASS PER BLOCK)

451 489 531 533 537  
536 534 387 400  
401 378 288 41

INTERNATIONAL CLASSIFICATION

B24B 1/00

GROUP  
ART UNIT

3723

ASSISTANT EXAMINER (PLEASE STAMP OR PRINT FULL NAME)

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PTO 270  
(REV. 5-91)

ISSUE CLASSIFICATION SLIP

U.S. DEPARTMENT OF COMMERCE  
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